Form PTO-1449 Attorney Docket No. Serial No. 191314-1011 To Be Assigned INFORMATION DISCLOSURE CITATION Applicant Mueller et al. (Use several sheets if necessary) Filing Date Group **Even Date Herewith** To Be Assigned U.S. PATENT DOCUMENTS Examiner Item **Document** Date Name Class Subclass Filing Date **Initials** Number H Appr priate Α US 6,493,420 B2 12/2002 Ruud 72 378 В US 6,353,656 B1 03/2002 LeVert et al. 378 72 C 04/1997 US 5,625,664 Berkeley 378 72 D US 5,155,751 10/1992 Chohata et al. 378 71 E US 5,148,458 09/1992 Ruud 378 72 F US 5,125,016 06/1992 Korhonen et al. 378 72 G US 5,111,493 05/1992 Siedband 378 103 Н 11/1991 US 5,068,883 DeHaan et al> 378 86 I US 5,686,631 08/1987 Ruud 702 42 J US 4,561,062 12/1985 Mitchell 702 40 K US 4,489,425 12/1984 Borgonovi 378 72 US 4,095,103 06/1978 Cohen et al. 378 72 FOREIGN PATENT DOCUMENTS Document Date Country Class Subclass Translation Number Yes No OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.) Article entitled "DRS-2 Digital Radioscopy System Accessories & Options" by SAIC Products, dated February 23, 2002, pp. 1-2; http://www.saic.com;products/inspection/drs2/drs2-options.html. Article entitled "DRS-2 Digital Radioscopy System Technical Specifications" by SAIC Products, dated February 23, ACH 2002, pp. 1-3; http://www.saic.com;products/inspection/drs2/drs2-tech.html. Article entitled "DRS-2 Digital Radioscopy System Overview" by SAIC Products, dated February 23, ΑCH 2002, pp. 1-2; http://www.saic.com;products/inspection/drs2/drs2.html. Article entitled "Technologies We Develop" by SAIC, dated February 23, 2002, pp. 1-2; ACH. http://www.saic.com/nde/.

* EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

NONDESTRUCTIVE EVALUATION: A STUDY OF BRASS; May, 1997; pgs. 1-73

EXAMINER'S SIGNATURE:

Q

DATE CONSIDERED:

Paul C. Schlesselman, B.S., M.S.; THESIS: FEASIBILITY OF USING X-RAY DIFFRACTION LINEWIDTH FOR

16.04.2004